

| | | | | |
|-----------------------------------|--|-------------------------|-----------------------------------------|--|
| Notice of References Cited | | Application/Control No. | Applicant(s)/Patent Under Reexamination | |
| | | 10/010,779 | EISENSTEIN, JONATHAN | |
| Examiner Tan Dean D. Nguyen | | Art Unit 3629 | Page 1 of 1 | |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--------------------------------------------------|-----------------|----------------|----------------|
| * | A | US-2001/0029470 | 10-2001 | Schultz et al. | 705/26 |
| * | B | US-2002/0010636 | 01-2002 | Immel, John J. | 705/26 |
| * | C | US-2001/0037206 | 11-2001 | Falk et al. | 705/1 |
| * | D | US-2002/0123983 | 09-2002 | Riley et al. | 707/1 |
| | E | US- | | | |
| | F | US- | | | |
| | G | US- | | | |
| | H | US- | | | |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--------------------------------------------------|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|-------------------------------------------------------------------------------------------|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.